ISO 12179:2026-05 (E)

Geometrical product specifications (GPS) - Surface texture: Profile - Calibration of contact (stylus) instruments

Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Normative references 1

3 Terms and definitions 1

4 Conditions of use 3
4.1 Components and configurations of the contact (stylus) instrument 3
4.2 Calibration of a configuration 3
4.3 Place of calibration 3
4.4 Defects 3

5 Measurement standards 3

6 Contact (stylus) instrument metrological characteristics 6
6.1 General 6
6.2 Residual profile calibration 6
6.3 Vertical profile component calibration 7
6.4 Horizontal profile component calibration 7
6.5 Profile coordinate system calibration 7
6.6 Total contact (stylus) instrument calibration 7

7 Calibration 7
7.1 Preparation for calibration 7
7.2 Evaluation of the residual profile 8
7.3 Calibration of the vertical profile component 8
7.3.1 Overall objective 8
7.3.2 Procedure 8
7.4 Calibration of the horizontal profile component 9
7.4.1 Overall objective 9
7.4.2 Procedure 9
7.5 Calibration of the profile coordinate system 9
7.5.1 Overall objective 9
7.5.2 Procedure 9
7.6 Calibration of the total contact (stylus) instrument 9
7.6.1 Overall objective 9
7.6.2 Procedure 9
7.7 Other calibrations 10

8 Measurement uncertainty 10
8.1 Information from the calibration certificate for a measurement standard 10
8.2 Measurement uncertainty during calibration of a measuring instrument 10

9 Contact (stylus) instrument calibration certificate 11

10 General information 11

Annex A (normative) Calibration of instruments measuring parameters of the motifs method 12

Annex B (normative) Calibration of simplified operator instruments for the measurements of surface texture 14

Annex C (informative) Example -- Roughness measurement standard parameter Ra 15

Annex D (informative) Concept diagram 18

Annex E (informative) Overview of profile and areal standards in the GPS matrix model 19

Annex F (informative) Relationship to the GPS matrix model 20

Bibliography 21